

An external test approach for network-on-a-chip switches

Raik, Jaan; Govind, Vineeth; Ubar, Raimund-Johannes 2002-2011 : 20th Anniversary compendium of papers from Asian Test Symposium 2011 / p. 185-190 : ill

Untestable fault identification in sequential circuits using model-checking

Raik, Jaan; Fujiwara, Hideo; Ubar, Raimund-Johannes; Krivenko, Anna 2002-2011 : 20th Anniversary compendium of papers from Asian Test Symposium 2011 / p. 257-262 : ill <https://ieeexplore.ieee.org/document/4711554>